SN54259, SN54LS259B, SN74259, SN74LS259B 8-BIT ADDRESSABLE LATCHES

- 8-Bit Parallel-Out Storage Register Performs Serial-to-Parallel Conversion with Storage
- Asynchronous Parallel Clear
- Active High Decoder
- Enable/Disable Input Simplified Expansion
- Expandable for N-Bit Applications
- Four District Functional Modes
- Package Options Include Ceramic Chip Carriers and Flat Packages in Addition to Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

These 8-bit addressable latches are designed for general purpose storage applications in digital systems. Specific uses include working registers, serial-holding registers, and active-high decoders or demultiplexers. They are multifunctional devices capable of storing single-line data in eight addressable latches, and being a 1-of-8 decoder or demultiplexer with active-high outputs.

Four distinct modes of operation are selectable by controlling the clear (CLR) and enable (G) inputs as enumerated in the function table. In the addressable-latch mode, data at the data-in terminal is written into the addressed latch. The addressed latch will follow the data input with all unaddressed latches remaining in their previous states. In the memory mode, all latches remain in their previous states and are unaffected by the data or address inputs. To eliminate the possibility of entering erroneous data in the latches, enable G should be held high (inactive) while the address lines are changing. In the 1-of-8 decoding or demultiplexing mode, the addressed output will follow the level of the D input with all other outputs low. In the clear mode, all outputs are low and unaffected by the address and data inputs.

The SN54259 and SN54LS259B are characterized for operation over the full military temperature range of -55° C to 125°C. The SN74259 and SN74LS259B are characterized for operation from 0°C to 70°C.



NC - No internal connection

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, J, N, and W packages.

PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SN54259, SN54LS259B, SN74259, SN74LS259B 8-BIT ADDRESSABLE LATCHES



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage (see Note 1)		
Input voltage: SN54259, SN74259.		 5.5 V
Operating free-air temperature range:		
	SN74259, SN74LS259B	
Storage temperature range		

NOTE 1; Voltage values are with respect to network ground terminal,



SN54259, SN74259 **8-BIT ADDRESSABLE LATCHES**

recommended operating conditions

		SN5	4259	SN74	1	
		MIN NO	M MAX	MIN NO	MAX N	UNIT
Supply voltage, VCC		4.5	5 5.5	4.75	5 5.25	V
High-level output current, IOH			-800		800	μA
Low-level output current, IOL			16		16	mA
Width of clear or enable pulse, $t_{\rm W}$		15		15		ns
Sotuci time t	Data	15		151		1
Setup time, t _{su}	Address	51		5↑		пs
	Data	O↑		01		<u> </u>
Hold time, th Address				201		ns
Operating free-air temperature, TA		55	125	0	70	°c

The errow indicates that the rising edge of the enable pulse is used for reference.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CC		S	N5425	9	SN74259			1				
			TESTICO		MIN	TYP‡	MAX	MIN	TYP‡	MAX	דואט				
⊻н	High-level input volta	ge			2			2			V				
VIL	Low-level input volta	je			T		B.0			0,8	V				
⊻ік	Input clamp voltage		VCC = MIN,	li = 12 mA	1		-1.5			-1.5	V V				
∨он	High-level output volt	age	V _{CC} = MIN, V _{IL} = 0.8 V,	VIH = 2 V, I _{OH} =800 μA	2.4	3.4		2,4	3.4	-	v				
Vol	Low-level output voltage		V _{CC} = MIN, VIL = 0.8 V,	V _{IH} = 2 V, IOL = 16 mA		0.2	0.4		0.2	0.4	v				
4	Input current at maxi	mum input voltage	V _{CC} = MAX,	V1 = 5.5 V			1			1	mA				
	High-level input	Ğ			80 40					80	<u> </u>				
ηн	current	Other inputs	V _{CC} = MAX,	VI = 2.4 V					40			40	μA		
4	Low-level input	ธิ	- 110 X		1		-3.2			-3.2					
ΊL	current	Other inputs	V _{CC} = MAX,	V _I = 0.4 V1.6		1,6		1,6		1,6				-1.6	- mA
los	Short-circuit output c	urrent \$	V _{CC} = MAX		-18		-57	-18		57	mА				
Icc	Supply current		Vcc = MAX,	See Note 2	+	60	90		60	90	mA				

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions,

All typical values are at $V_{CC} = 5 V$, $T_A = 25 ^{\circ}C$. §Not more than one output should be shorted at a time.

NOTE 2: ICC is measured with the inputs grounded and the outputs open.

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	түр	MAX	UNIT						
^t PHL	CLR	Any (1			16	25	лs						
^t PLH	Data	1 100	A	Any Q	1		14	24					
^t PHL	Data	Any Q	CL = 15 pF,		11	20	⊓s						
tplH	A - J -J	Αηγ Ο	Αηγ Q	Αηγ Ο	Απγ Q	Αηγ Ο					15	28	
TPHL	Address						See Note 3		17	28	ns		
^t PLH	 G	A			12	20							
tPHL	ف	Any Q				20	ns						

switching characteristics, VCC = 5 V, TA = 25°C

 t_{PLH} = propagation delay time, low-to-high-level output

tpHL = propagation delay time, high-to-low-level output

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



TTL Devices

SN54LS259B, SN74LS259B 8-BIT ADDRESSABLE LATCHES

recommended operating conditions

			SI	154LS2	69B	SN74LS259B			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.6	4.75	5	5,25	V
VIH	High-level input voltage	·····	2			2			V
VIL	Low-level input voltage				0.7			0.8	v
юн	High-level output current				- 0.4			- 0.4	mΑ
IOL	Low-level output current				4			8	mΑ
		Glow	17			17			
^t w	Puise duration	CLR low	10			10			ПS
		Data before G ↑	20			20			
tsu	Set up time	Address before G1	17			17			ns
		Address before G↓	0			0			
		Data after G 1	0			0			
th	Hold time	Address after G †	0			0			ns
Τ _Α	Operating free-air temperature		- 55		1 2 5	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS [†]		Sħ	SN54LS2598			SN74LS2598			
	TEST CONDITIONS.		MIN	түр	MAX	MIN	түр	MAX	UNIT	
Vικ	V _{CC} = MIN, I _I = - 18 mA				- 1.5			- 1.5	v	
Voн	$V_{CC} = MIN$, $V_{IH} = 2 V$, $V_{IL} = MAX$, $I_{OH} = -0.4 \text{ mA}$		2,5	3,4		2.7	3.4		v	
Vol	V _{CC} = MIN, V _{IH} = 2 V,	IOL = 4 mA		0,25	0,4		0.25	0.4	v	
VUL	VIL - MAX	101 = 8 mA					0,35	0.5	Ň	
- Ц	V _{CC} = MAX, V ₁ = 7 V				0.1			0.1	mΑ	
IН	V _{CC} = MAX, V ₁ = 2.7 V				20			20	μA	
hr.	V _{CC} = MAX, V ₁ = 0.4 V				- 0.4			- 0.4	mA	
los§	V _{CC} = MAX		- 20		- 100	- 20		- 100	mΑ	
Icc	V _{CC} = MAX, See Note 2			27	36		22	36	mA	

[†]For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions

[‡]All typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$.

§Not more than one output should be shorted at a time, and duration short-circuit should not exceed one second.

NOTE 2: I_{CC} is measured with the inputs grounded and the outputs open.

switching characteristics, VCC = 5 V, TA = $25^{\circ}C$

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CON		MIN	түр	МАХ	UNIT
^t PHL	CLR	Алу Q				12	18	ns
tPLH	Data	Any Q				19	30	-
TPHL	Data	C _L = 15 pF,	0 15 - 5	$\mathbf{R}_{l} = 2 \mathbf{k} \Omega_{l}$		13	20	ns
^t PLH	Address			RL - 2 K32,		17	27	
^t PHL	Address	Any C	266 1016 2			14	20	ПS
^t PLH	G	Any Q				15	24	
^t PHL		Any Q	<u> </u>			15	24	∩\$

tpLH = propagation delay time, low-to-high-level output

 t_{PHL} = propagation delay time, high-to-low-level output

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



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